

# alfamation

an inTEST Company



## Functional Testing of Micro-Optics for Automotive™

**Micro-optics**

SUMMIT & EXPO

Amsterdam

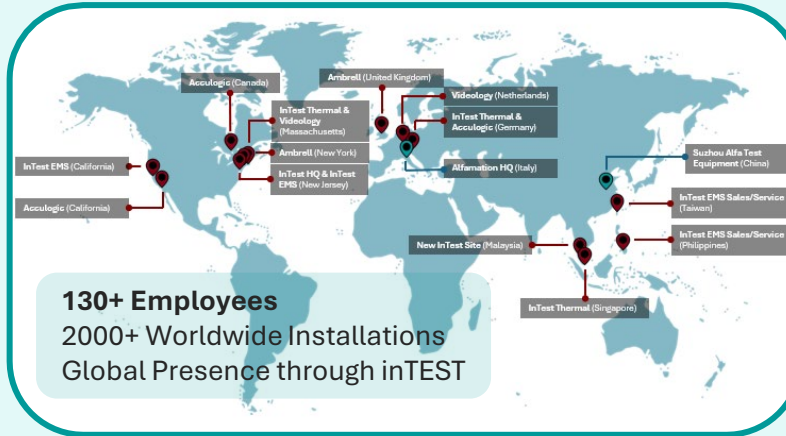
2<sup>nd</sup> & 3<sup>rd</sup> December 2024

*Simone Francavilla*

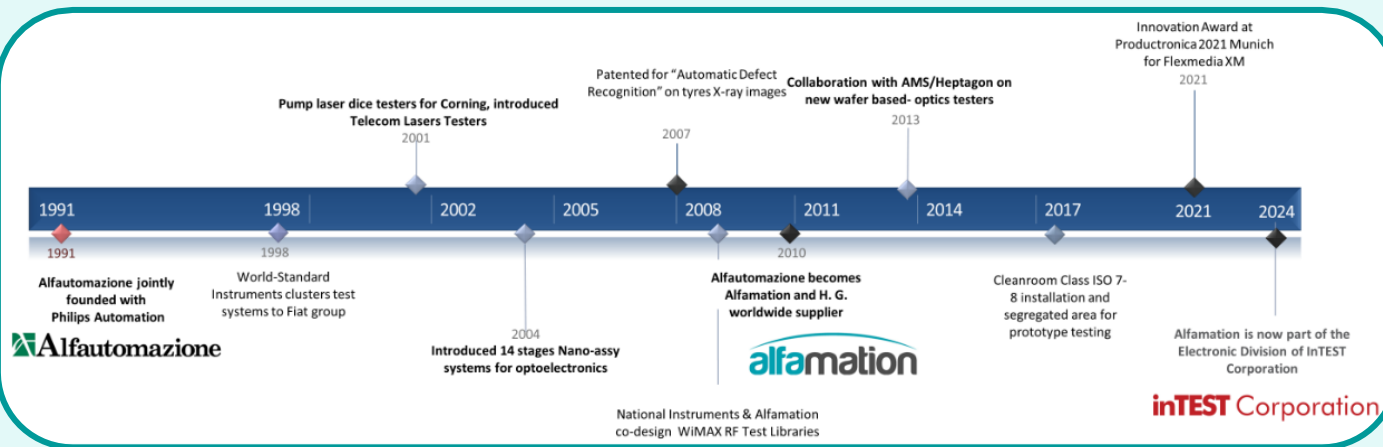
*Project Leader and Product Manager*

# Alfamation - 33 years of expertise

Headquarters in Lissone (MB)  
Italy  
Part of inTEST Corp. (NJ USA)  
NYSE: INTT



- Strong R&D and Engineering
- Expertise in Optics
- Deep knowledge in Image Processing
- Experience in Optoelectronics and Photonics



Diversified Global Manufacturer



- RF & Wireless
- Infotainment & Telematics
- 5G and V2X
- Consumer Electronics
- Displays
- PCBA Functional Test
- Audio Amplifier Test
- 32 Simultaneous Audio Channel Testing

## Hyperion™ Common Test Platform



## flexmedia XM

MULTIPLE INSTRUMENTS, ONE FAMILY

- Specialty Test Modules
- Audio-Video Generators/Analyzers
- Camera Simulators
- Ethernet-powered, OS-Agnostic



BATTERY MANAGEMENT PCBA TEST



Single-Site Drawer



Dual-Site Turntable



Dual-Site Drawer

## Pixelshooter™ Automated Display Tester

## WALOT

Wafer-Level-Optics Tester  
For High-Volume Manufacturing





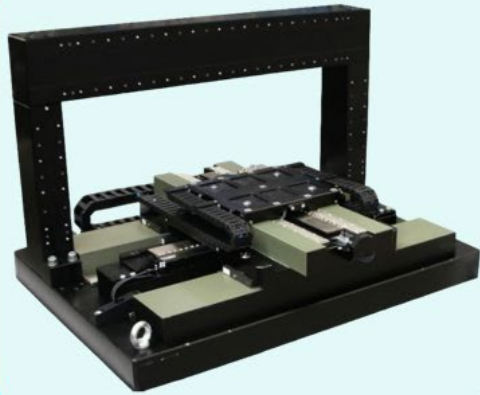


# **What makes a good Automated Test Equipment?**

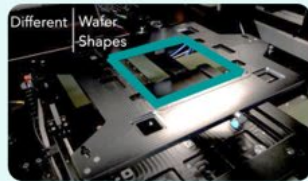
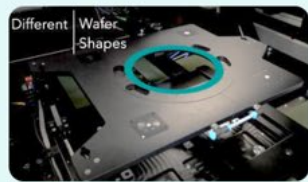
# Cost Optimization

- No well-established standard to refer to
- Multiple variants of the “same” product
- Different devices, different shapes and sizes

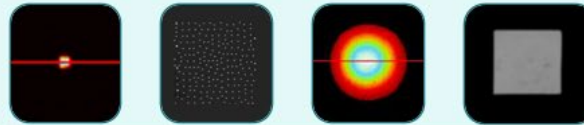
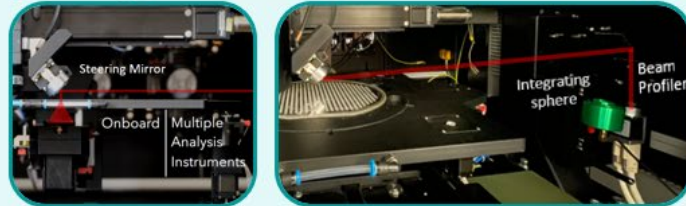
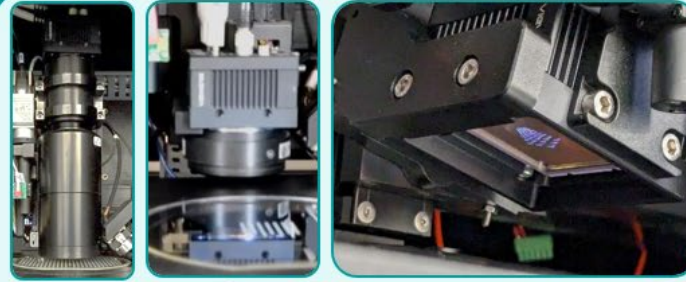
# Modularity



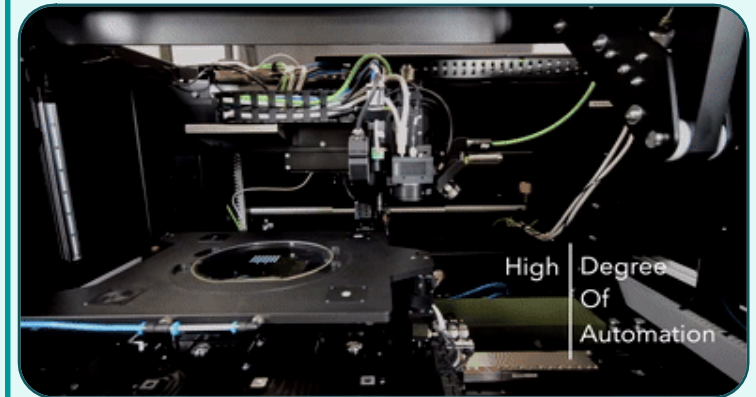
Base Platform - XY Wafer Handling System



Multiple Chuck Options



Multiple Instruments Configurations



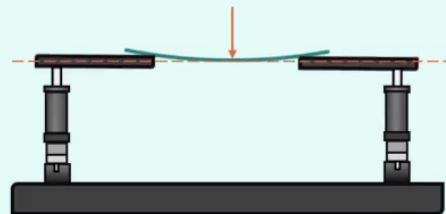
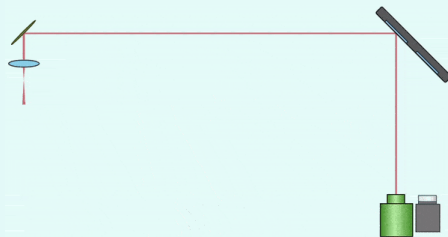
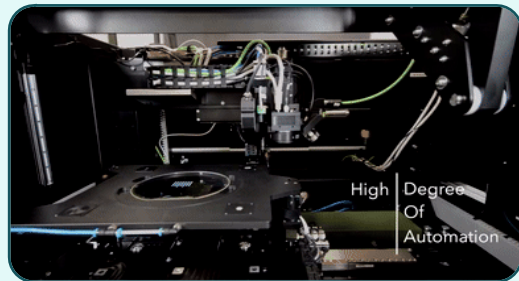
Fully Configured Setup!

- Well-established common platform to concentrate efforts on application challenges
- Common-base of components and spare-parts
- Reduced maintenance and semi-automatic calibrations
- One platform, multiple applications



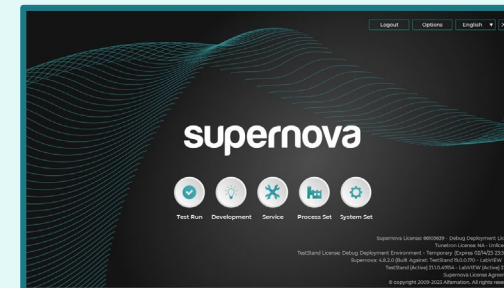
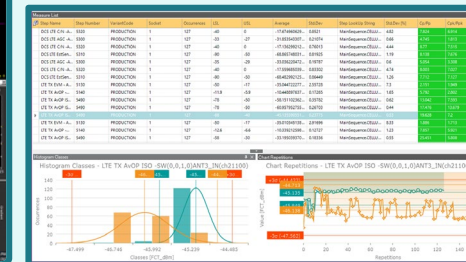
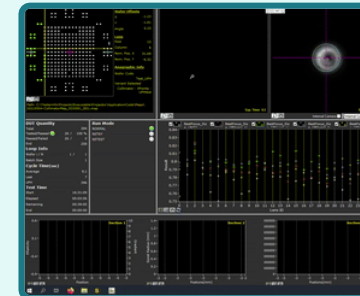
# Flexibility

# Hardware



- Multiple Automated Degrees of Freedom

## Software

[illegible]

- User-friendly and powerful GUI

- Multiple Degrees of freedom allowing to test different product variants without retooling and recalibrations
- A powerful and user-friendly software interface to adjust test parameters  
(Supernova™ : Alfamation proprietary test sequencer based on NI Teststand)

# Efficiency

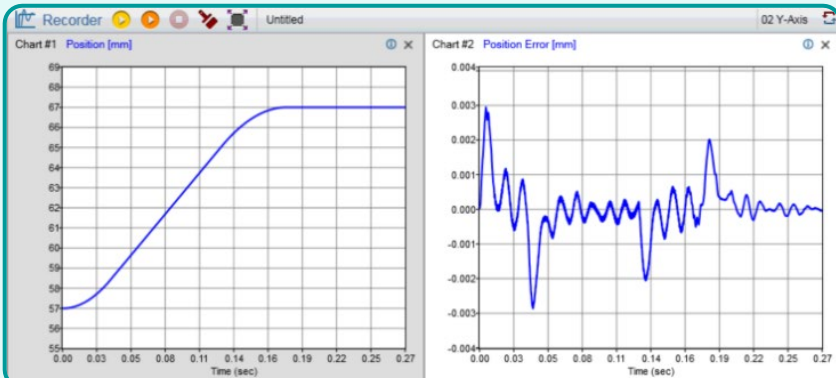
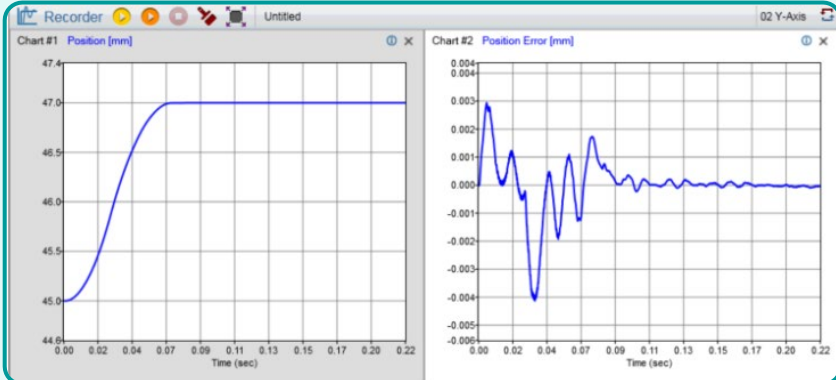
- Fast solution for an efficient process
- Robust and Stable solution to avoid false calls and insightful process characterization



# High Throughput

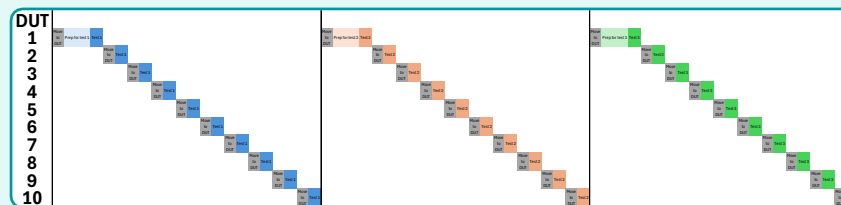
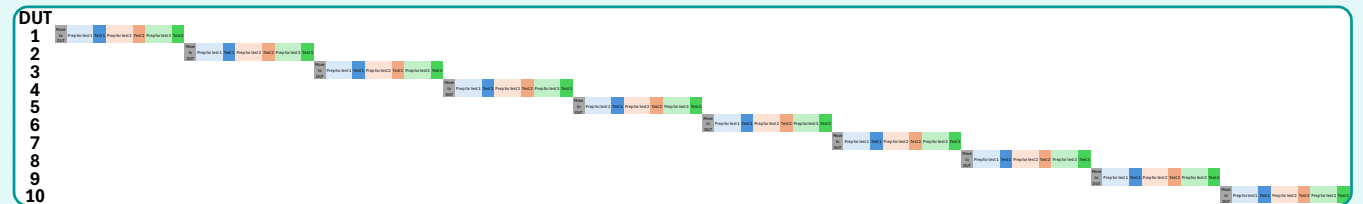
- Algorithms, Image Processing and results logging are all run in parallel to movements and positioning to remove or reduce the overhead

Parallel Threads



Step Size	Stepping Time (Settling within 300 nm)
2 mm	90 ms
10 mm	200 ms

Fast and Reliable Positioning




Reduced Test Time  
Same Test Scope

Batch Logic

# Reliability

- According to the Automotive Industry Action Group (AIAG) if your measurement system's variation is less than 10% of process's variation, then it is acceptable.



Percentage of Process Variation (%R&R)	Acceptability
Less than 10%	The measurement system is acceptable
Between 10% and 30 %	The measurement system is acceptable depending on the application, the cost of the measurement device, cost of repair, or other factors.
Greater than 30%	The measurement system is not acceptable and should be improved

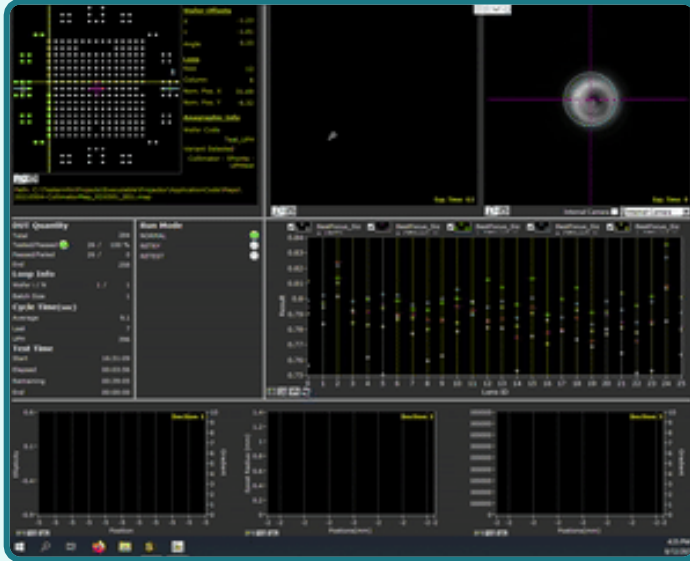


# Production Plant Challenges

- Compatibility with Mass-Production environment



# Production and Clean Room Compatibility



Operator-Friendly User Interface

- Network Integration
- MES Interface

Plant Interface

- Automatic Serial Number reading and Alignment procedure
- Robotized Automatic Wafer loading compatibility

Reduced Operator Workload

- Ventilation and Filters Unit for Clean Room integration

Clean Room Compatibility

# MLA Decorative Lighting

## Welcome Carpet and “Driving Intensions”

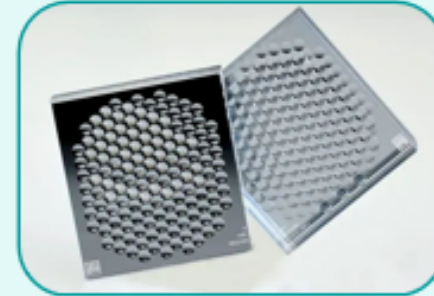


Welcome Carpet

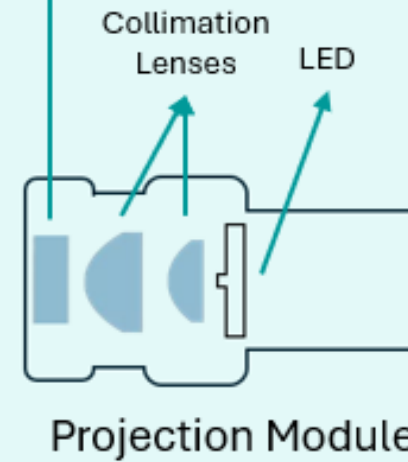


“Driving Intensions”

MLA (Micro Lens Array)

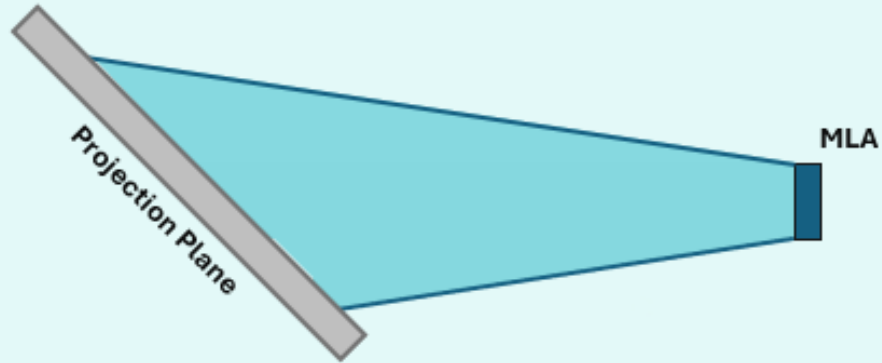


Tested at Wafer-Level!

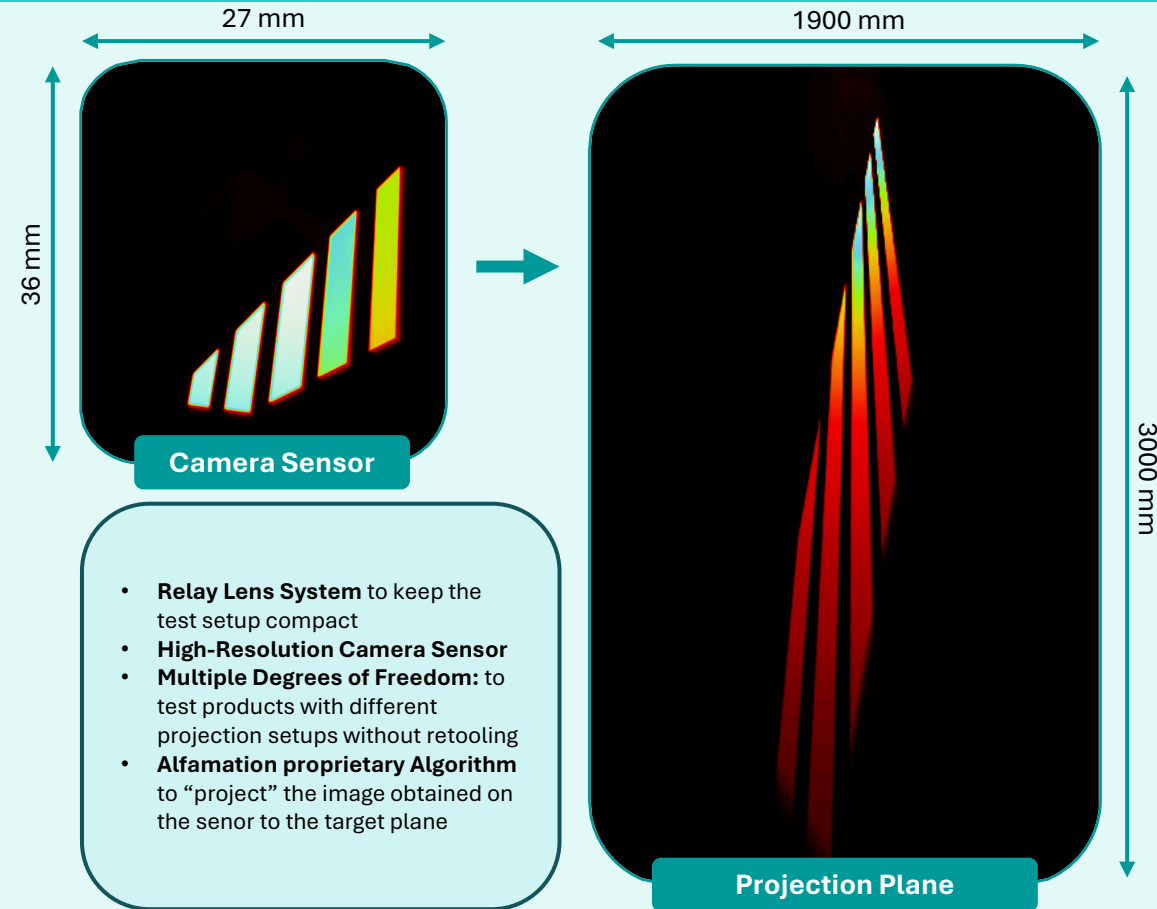
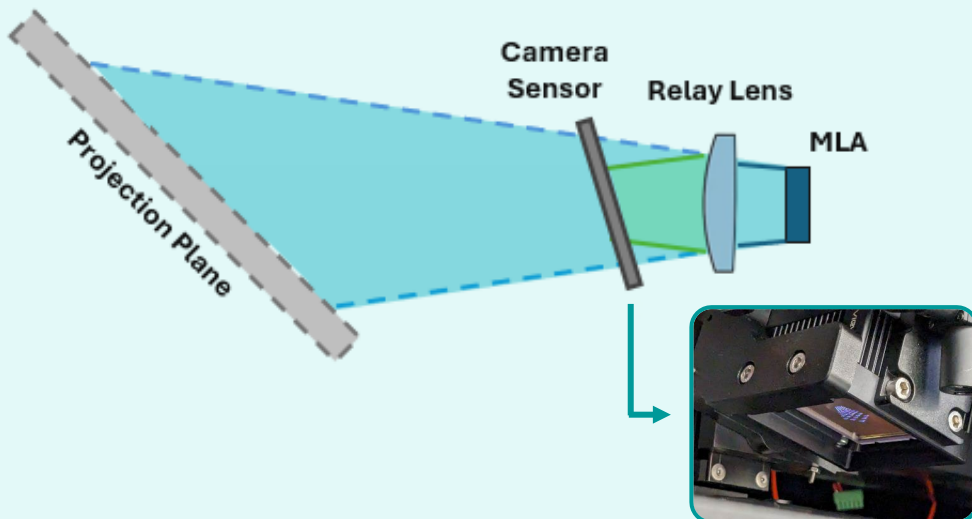


# MLA Decorative Lighting Setup – Projection on Target Plane (i.e. Street)

Use-case Setup



Testing Setup



**Test Metrics:** Relative Brightness, Contrast\Gradient, Cross Talk\Ghost, Chromatic Aberration

**Speed:** Up to 2800 UPH (Units per hour)

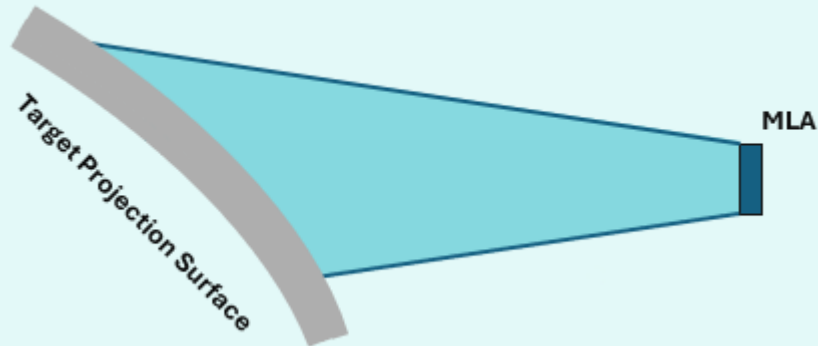
**Stability:** Gage R&R < 10%

Performance

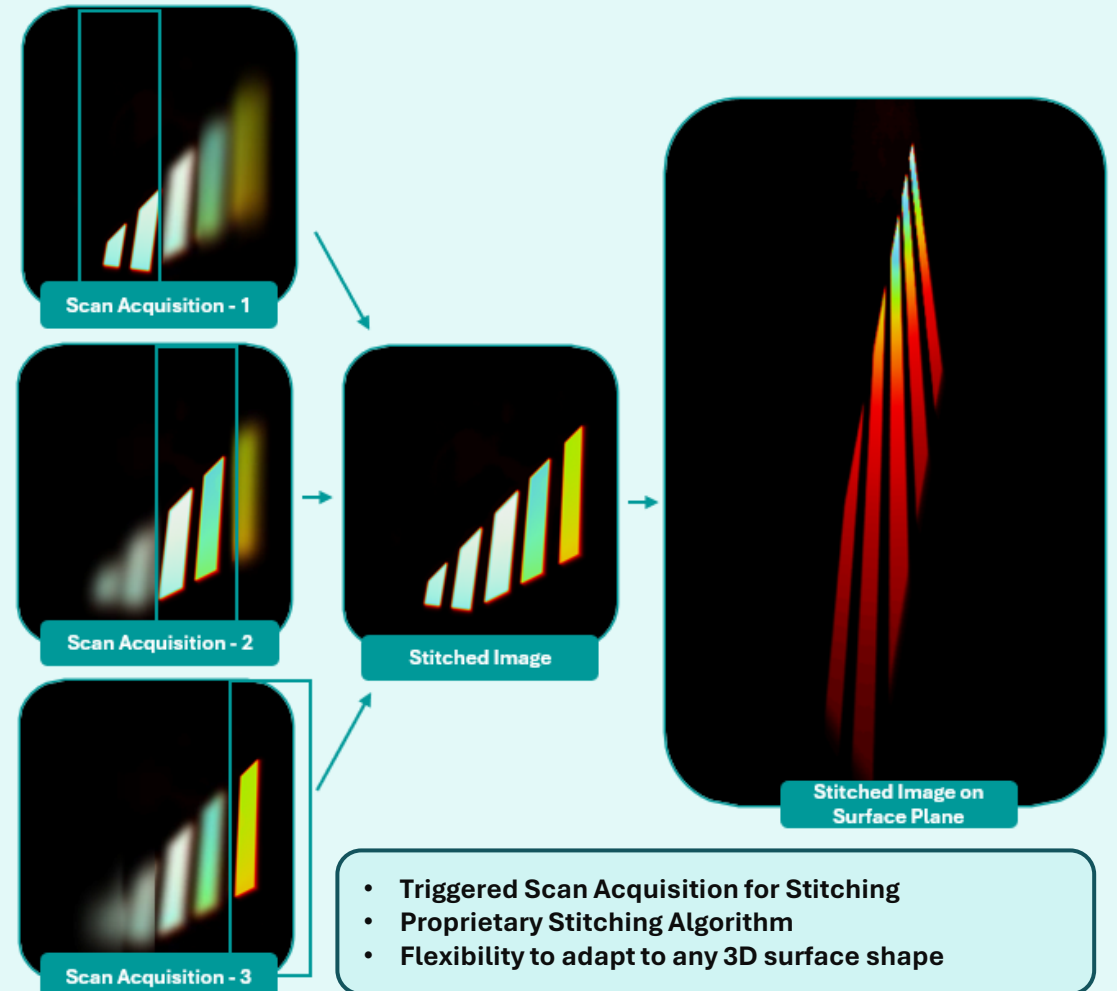
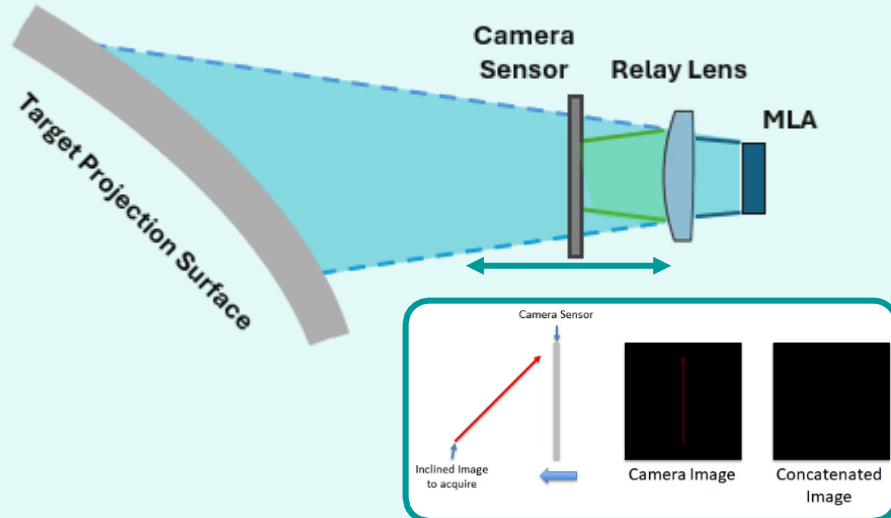


# MLA Decorative Lighting Setup – Projection on Arbitrary Surface (i.e. Dashboard)

Use-case Setup



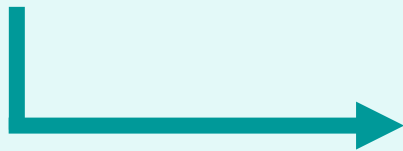
Testing Setup



# Collaborations

## Testing Micro-Optics and Assembled Modules

- This is just a portion of **Alfamation** portfolio and capabilities!
- **Alfamation** is looking for:
  - **instruments and test methods** to integrate in our test platforms
  - new **micro-optics and photonics test challenges**
- **Alfamation**, by leveraging its strong engineering capabilities can:
  - supply **innovative automated test solutions**
  - develop **new test methods**
  - **not only at wafer level!**





# VISIT US AT OUR BOOTH!

## CONTACTS



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### EUROPE HEADQUARTERS

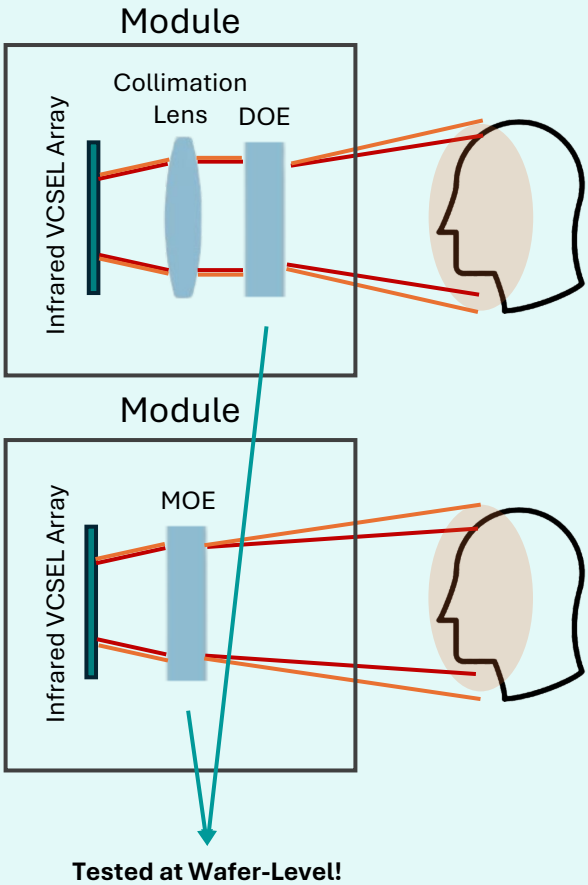
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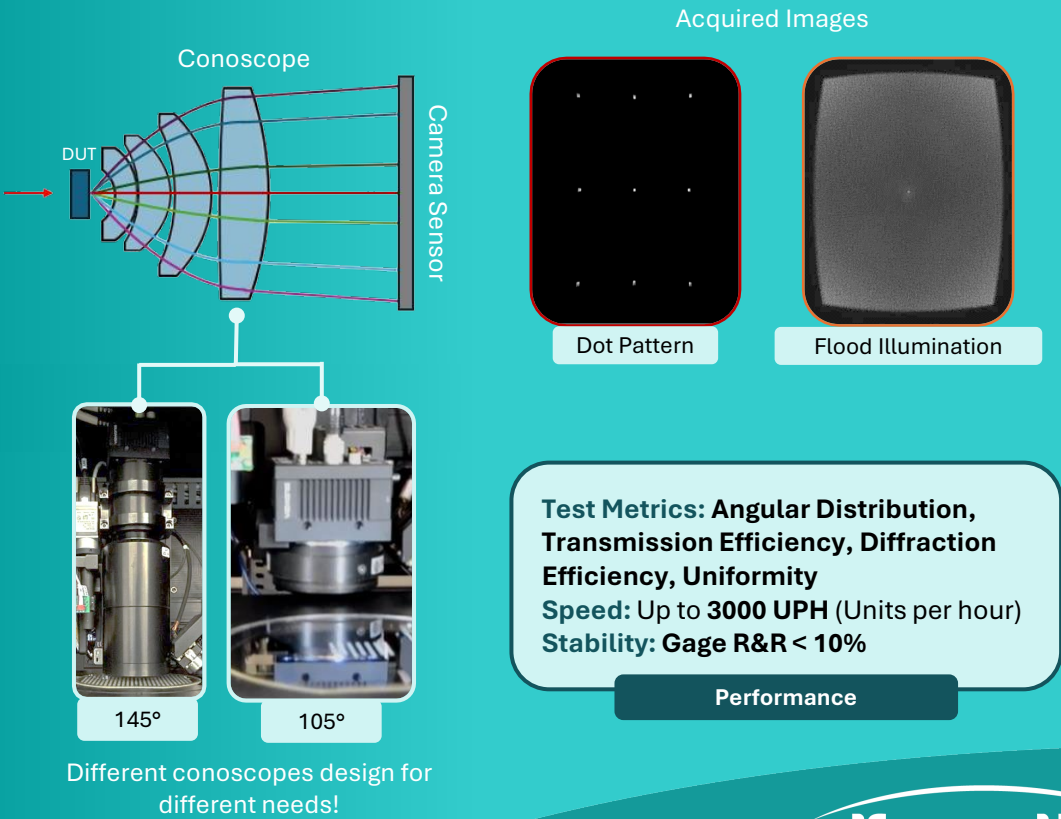
# Conoscopy Mode: DOEs and MOEs testing



DOEs and MOEs are used for both **Dot Pattern Projection (red)** and **Flood Illumination (orange)** in the face id and gesture recognition procedure.

# Conoscopy Mode: Test Principle and Configuration

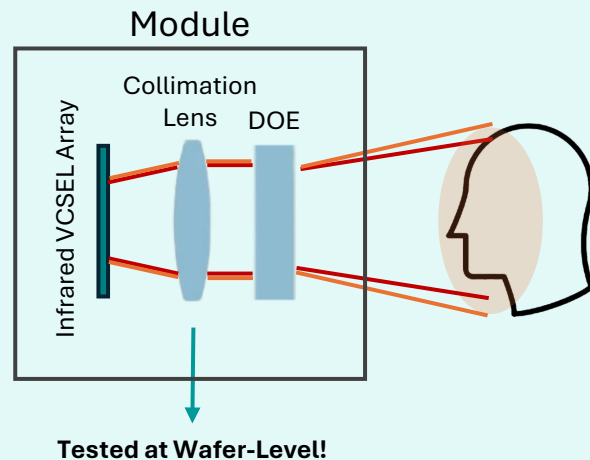
- High-resolution camera + Conoscope
- High acceptance angle
- Angular Map



# Collimated Beam Profiling Mode: Collimation Lenses testing

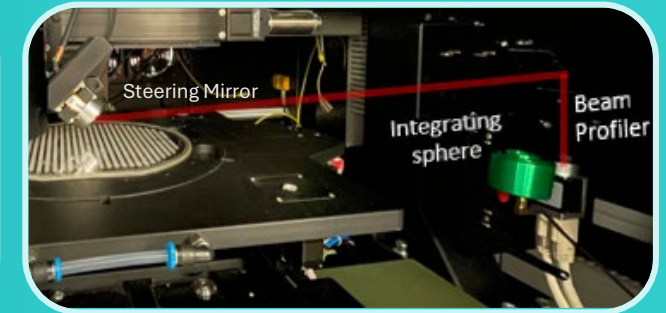
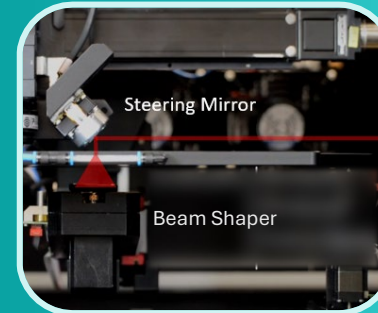


**Collimation Lenses** are components used in a very wide range of applications. In consumer electronics, they are often paired with DOEs for **face ID** and **gesture recognition**.



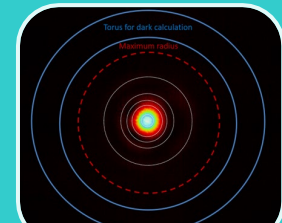
# Collimated Beam Profiling Mode: Test Principle and Configuration

- **Distance sensor** for wafer warpage
- **Focus scan** for best focus and FFL measurement
- **Steering mirror, camera sensor and integrating sphere**



**Test Metrics:** Spot Size, Transmitted Power, Flange Focal Length, Effective Focal Length  
**Speed:** Up to 1500 UPH (Units per hour)  
**Stability:** Gage R&R < 10%

Performance



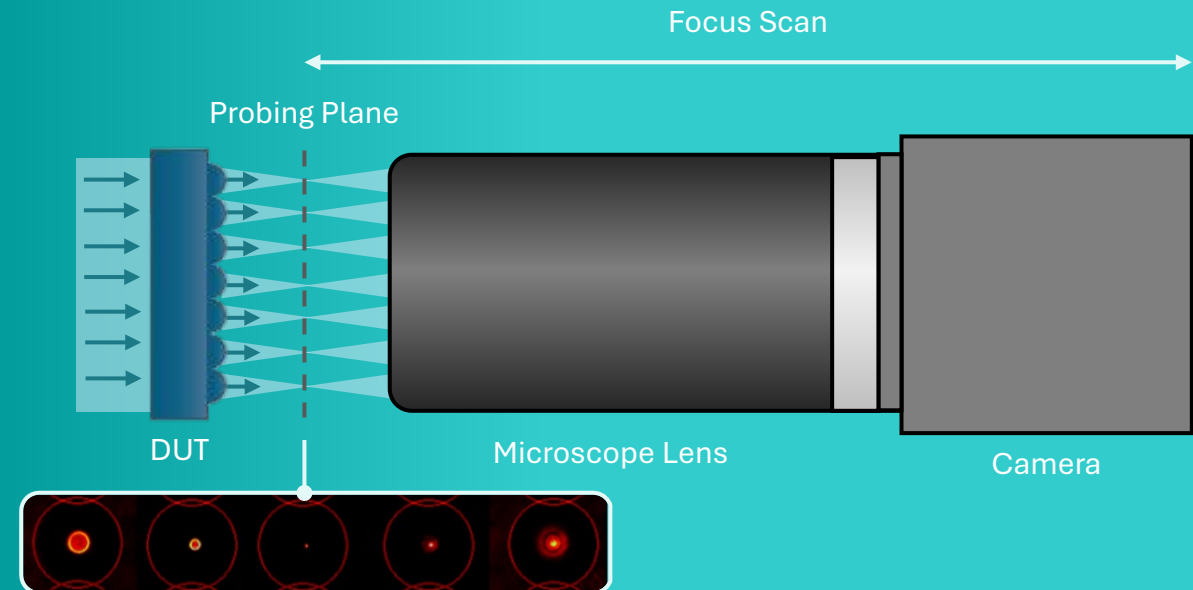
Spot on Beam Profiler

# Coupling Micro-Optics Mode: Telecom and Imaging optics testing

**Coupling optics** are often used in telecommunication industry and for imaging purposes.



# Coupling Micro-Optics Mode: Test Principle and Configuration



**Test Metrics:** Efficiency, Flange Focal Length, Uniformity  
**Speed:** Up to **1500 UPH** (Units per hour)  
**Stability:** Gage R&R < 10%

Performance